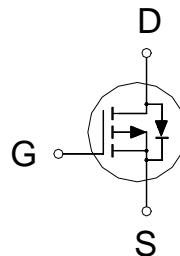


P-Channel Logic Level Enhancement Mode Field Effect Transistor
Product Summary:

BV_{DSS}	-20V
$R_{DS(on)}$ (MAX.)	100m Ω
I_D	-4.5A


Pb-Free Lead Plating & Halogen Free

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 12	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	-4.5	A
	$T_A = 70^\circ\text{C}$		-3.3	
Pulsed Drain Current ¹		I_{DM}	-18	
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	2.5	W
	$T_A = 70^\circ\text{C}$		1.6	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$	6	50	°C / W
Junction-to-Ambient ³	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$
³50°C / W when mounted on a 1 in² pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

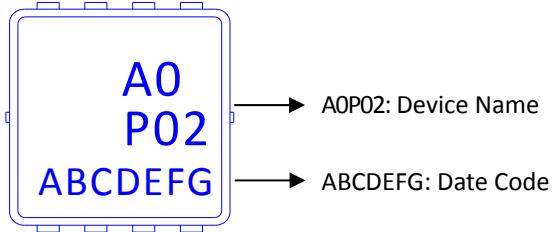
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-0.3	-0.75	-1.2	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 12\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -5\text{V}, V_{\text{GS}} = -4.5\text{V}$	-4.5			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -3.4\text{A}$		83	100	$\text{m}\Omega$
		$V_{\text{GS}} = -2.5\text{V}, I_D = -2.5\text{A}$		110	135	
		$V_{\text{GS}} = -1.8\text{V}, I_D = -1\text{A}$		140	180	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -5\text{V}, I_D = -3\text{A}$		4.5		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -10\text{V}, f = 1\text{MHz}$		450		pF
Output Capacitance	C_{oss}			58		
Reverse Transfer Capacitance	C_{rss}			41		
Total Gate Charge ^{1,2}	Q_g	$V_{\text{DS}} = -10\text{V}, V_{\text{GS}} = -4.5\text{V}, I_D = -3\text{A}$		5.4		nC
Gate-Source Charge ^{1,2}	Q_{gs}			1.0		
Gate-Drain Charge ^{1,2}	Q_{gd}			1.3		
Turn-On Delay Time ^{1,2}	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = -10\text{V}, I_D = -1\text{A}, V_{\text{GS}} = -4.5\text{V}, R_{\text{GS}} = 6\Omega$		10		nS
Rise Time ^{1,2}	t_r			20		
Turn-Off Delay Time ^{1,2}	$t_{\text{d}(\text{off})}$			15		
Fall Time ^{1,2}	t_f			12		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ\text{C}$)						
Continuous Current	I_S				-4.5	A
Pulsed Current ³	I_{SM}				-18	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{\text{GS}} = 0\text{V}$			-1.2	V

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

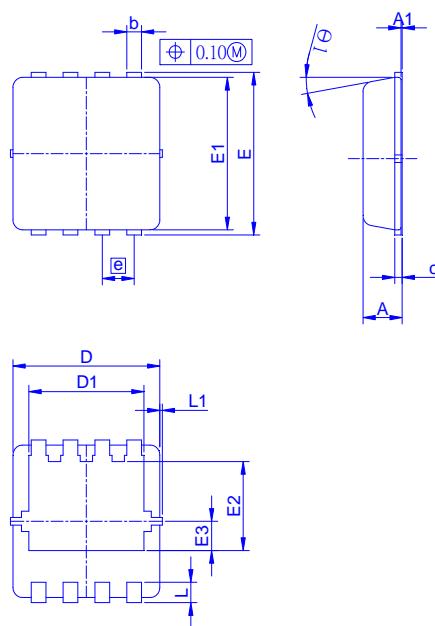
³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: LBOP02B for EDFN 3 x 3



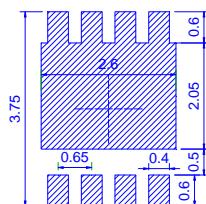
Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D1	E	E1	E2	E3	e	L	L1	θ1
Min.	0.70	0	0.24	0.10	2.95	2.25	3.15	2.95	1.65			0.30		0°
Typ.	0.80		0.30	0.152	3.00	2.35	3.20	3.00	1.75	0.575	0.65	0.40	0.13	10°
Max.	0.90	0.05	0.37	0.25	3.15	2.45	3.40	3.15	1.96			0.50		12°

Recommended minimum pads



TYPICAL CHARACTERISTICS

